

➔ PN-12α·PN-50α PN type checker ; Contact type(PN-12α) & Non-contact type(PN-50α)

PN-12α



Selling Points

Principle: Thermo-electromotive force(seebek effect)
Possible to check most figure of sample such as single crystalline silicon wafer, bulk, ingot and so on

*Please select from 2 types;

- 1) 2 probe ver.(Hot probe, Cold probe),
- 2) 1 probe ver.(Hot & Cold probe)

Details

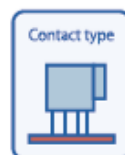
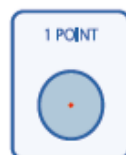
Sample sizes

more than 2 inch

Measuring range

PN Checking range in resistivity : 1m ~ 20k Ω·cm

*Polycrystalline silicon, thin film on wafer, MultiOxidized film on wafer surface are can not judgement



PN-50α



Selling Points

Principle: Photovoltaic effect by light pulse irradiation
No damage and no stain by Non-contact method
Possible to check even oxidized film on wafer surface
Instantly discrimination by optical pulse illuminate

Details

Sample sizes

more than 30x30mm

Measuring range

PN Checking range in resistivity : 0.1~1,000Ω·cm

